HKN ECE 110 Review Session Exam 3

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Quick Announcement

- •HKN PHYS 212 Exam 3 Review Session
 - •Sunday, 4/22, 2-4pm in ECEB 1013

BJT Transfer Characteristic

- •The transfer characteristic of a BJT relates the output voltage, $V_{CE}=V_{o}$, to its input voltage, V_{i} .
- •We can deduce the regions of operation and thus the important values from the graph

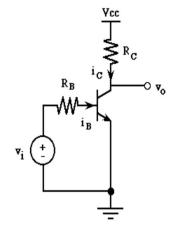
$$V_{o1} = V_{CC}$$

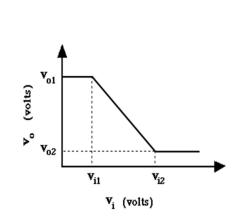
$$V_{o2} = V_{CE,SAT}$$

$$V_{i1} = V_{BE,ON}$$

• $V_{i2} = V_i^* = \text{minimum input to enter saturation}$

•Gain =
$$G = -\frac{\beta R_C}{R_B}$$
 = slope in active region





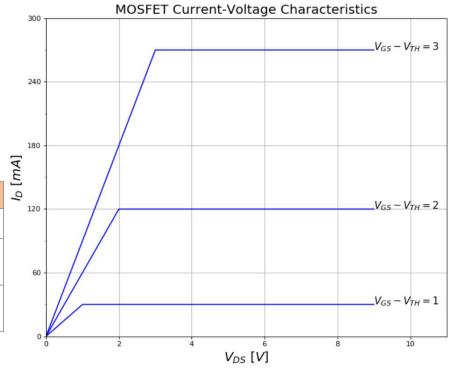
BJT Power

- •In order to calculate the power of a BJT, we consider the power contributed by each junction we analyze: Base-Emitter and Collector-Emitter
- $P_{BJT} = V_{BE,ON}I_B + V_{CE}I_C$
- •If the BJT is off, power is zero.
- •We must check to see if the transistor is in the active or saturated region as usual
- •Notice that the Base-Emitter (1st) term is typically much smaller than the Collector-Emitter (2nd) term since $I_C\gg I_B$ due to β

Metal-Oxide-Semiconductor Field-Effect Transistor (MOSFET)

- •Three terminal device: gate, source, drain
- Comes in two flavors, nMOS and pMOS
- ${}^{ullet}V_{TH}$ is a property of the specific MOSFET
- •Be comfortable interpreting I-V Characteristic of MOSFET

Conditions	Mode	Behavior under Linear Model
$oxed{V_{GS} < V_{TH}}$	OFF	$I_D=0$
$oxed{V_{GS} > V_{TH} \ V_{DS} > V_{GS} - V_{TH}}$	ACTIVE	$I_D = k(V_{GS} - V_{TH})^2 ig $
$oxed{V_{GS} > V_{TH} \ V_{DS} < V_{GS} - V_{TH}}$	OHMIC	$I_D = k(V_{GS} - V_{TH})V_{DS} vert$



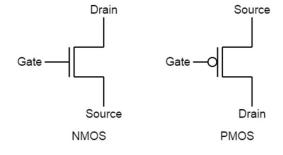
Complementary MOS Logic (cMOS)

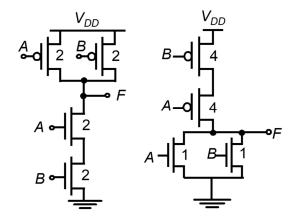
Combine NMOS and PMOS transistors in order to perform a logical operation

• i.e. AND, NOR, NOT

NMOS and PMOS are biased differently

 $\bullet\,$ NMOS, source connects to ground; PMOS, source connects to V_{DD}

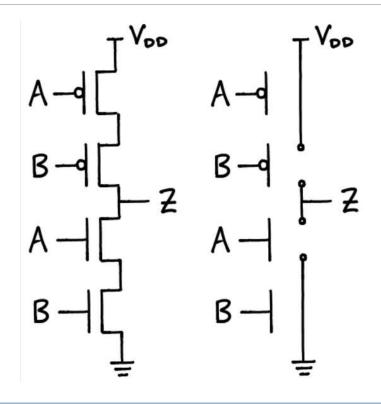




Input (@ Gate)	nMOS	pMOS
0	Non-Conducting	Conducting
1	Conducting	Non-Conducting

Improper CMOS

- •A CMOS circuit is considered *proper* if:
 - The output can only be connected to one of V_{DD} or Ground at a time
- •A CMOS circuit is considered *improper* if:
 - The output can be connected to both V_{DD} and Ground simultaneously by some input combination
 - The output can be connected to neither V_{DD} nor Ground simultaneously by some input combination



CMOS Power

$$P = nafCV_{DD}^2$$

- •n = number of capacitors/transistors
- •a = activity factor
- •f = frequency
- •C = capacitance
- • V_{DD} = supplied voltage

Signal-to-Noise Ratio (SNR)

•Signal-to-Noise Ratio gives us an understanding of the amount of noise distortion in a system

•SNR =
$$\frac{P_{signal}}{P_{noise}}$$

•Remember that the average power for a time-varying signal requires \emph{V}_{rms}

•
$$P_{avg} = \frac{V_{rms}^2}{R}$$
, $V_{rms}(sine) = \frac{A}{\sqrt{2}}$, $V_{rms}(sq.wave) = A\sqrt{Duty\ Cycle}$

We can also express SNR as follows

•SNR =
$$\frac{P_{signal}}{P_{noise}} = \frac{\frac{V_{rms,signal}^2}{R}}{\frac{V_{rms,noise}^2}{R}} = \left(\frac{V_{rms,signal}}{V_{rms,noise}}\right)^2$$

Sampling

•When we convert from a continuous-time analog signal (function of time) to a discrete-time digital signal (function of n), we are performing sampling, or Analog/Digital (A/D) conversion

•We relate the sampled (digital) signal to the original (analog) signal by:

$$x[n] = x(nT_s)$$

ullet n is the index for the "nth" sample, $T_{\mathcal{S}}$ is the sampling period

Wise Words to Make your Score Soar

- Use your note sheet more like a study tool
- Spend your time showing what you know
- Make sure to get through the whole exam
- Take the time to relax before your exam